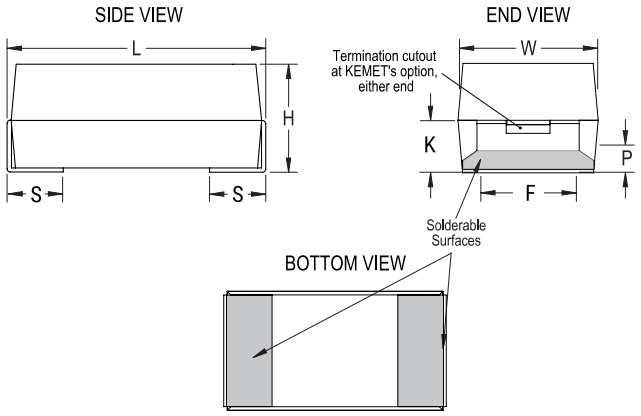
CWR19DC337KCHB

Aliases (T419H337K006CC4251)

T419 CWR19, Tantalum, MnO2 Tantalum, Military/High Reliability, 330 uF, 10%, 6 VDC, SMD, MnO2, Molded, Military Equivalent, C (0.01%/1000 Hrs), 900 mOhms, 3.17 mm, 2815 / 7238



Click here for the 3D model.

General Information	
Series	T419 CWR19
Dielectric	MnO2 Tantalum
Style	SMD Chip
Description	SMD, MnO2, Molded, Military Equivalent
RoHS	No
Prop 65	**WARNING:** Cancer and reproductive harm - https://www.p65warnings.ca.gov./
SCIP Number	652b281f-d242-4453-bc44-0655d646cec3
Termination	Hot Solder Dipped
Qualifications	MIL-PRF-55365/11, CWR19 Style
Typical Component Weight	349.01 mg
Notes	Note: When Option C Is Selected For Lead Material, Add An Additional 0.38mm To The Tolerances For "L", "W", "H", "K" ,"F" And "S".
MSL	1

Dimensions	
L	7.24mm +/-0.38mm
W	3.81mm +/-0.38mm
H	2.79mm +/-0.38mm
S	1.27mm +0.25/-0.13mm
F	3.68mm +0.13/-0.51mm
K	1.52mm MIN
P	0.76mm MIN

Packaging Specifications	
Packaging	T&R, 178mm
Packaging Quantity	500

Specifications	
Capacitance	330 uF
Tolerance	10%
Voltage DC	6 VDC (85C), 4 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	85°C
Dissipation Factor	10% 120Hz 25C
Failure Rate	C (0.01%/1000 Hrs)
ESR	0.9 Ohms (100kHz 25C)
Ripple Current	408 mA (rms, 100kHz 25C)
Leakage Current	20 uA (5min 25°C)
Testing and Reliability	Surge Testing (10 Cycles At -55C +/-5C And +85C +/-5C After Weibull)

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